

Notice of References CitedApplication/Control No.
09/683,761Applicant(s)/Patent Under
Reexamination
SMITH ET AL.Examiner
LIEN TM NGOArt Unit
3727

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,829,611	11-1998	Beck, James M.	215/252
	B	US-5,975,369	11-1999	Yurkewicz et al.	222/153.06
	C	US-5,992,692	11-1999	Boissay, Michel Pierre	222/83
	D	US-6,321,924	11-2001	Yurkewicz et al.	215/251
	E	US-6,050,452	04-2000	Pradinas, Claude	222/153.02
	F	US-3,910,463	10-1975	Reese, Stanley	222/153.14
	G	US-4,805,807	02-1989	Perne et al.	222/153.06
	H	US-5,096,077	03-1992	Odet et al.	215/211
	I	US-5,429,255	07-1995	Glynn, Kenneth P.	215/223
	J	US-5,265,777	11-1993	Weinstein, Jack	222/517
	K	US-5,104,008	04-1992	Crisci, Robert E.	222/153.07
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Dewig et al., Pub. US 2003/0034347 A1, Feb. 20, 2003
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.